4D InSpec[®] Surface Gauge

- Instant 3D Surface Measurement
- Measure Defects and Features from 4 µm–2.5 mm Deep
- Measure Large Components Directly—No Replication Needed
- Easy Measurement of Complex Geometries
- Handheld, Workstation or Robotic Operation

The 4D InSpec Surface Gauge is the first handheld, precision instrument for non-contact measurement of surface features and defects. With micrometer-level resolution, portability, affordability and ease-of-use, 4D InSpec puts high resolution measurement on the factory floor, in machine shops and deployed environments.

4D InSpec brings 3D measurement to the factory floor, to quantify pits, scratches, nicks, dents, bumps, porosity and other features from 0.0002" to 0.1" (5 μ m–2.5 mm) deep or tall. 4D InSpec is far more repeatable and accurate than visual comparison techniques typically used for surface defect measurements. Unlike high-end metrology systems it is rugged, flexible and affordable, to measure a wide range of part geometries in the most challenging environments.

The 4D InSpec can be handheld to access tight corners or to sample large surfaces. An optional fold mirror accessory lets the system function like a borescope to access blind holes and inner diameters. One-button operation and immunity to sensor movement make it easy to align and measure, while a rugged aluminum housing and single cable tether withstand the rigors of daily use.

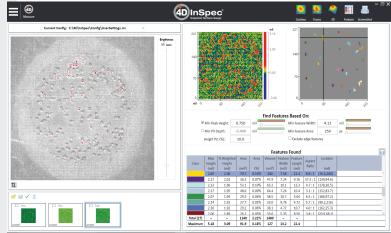
In a workstation configuration 4D InSpec makes it fast and easy to obtain repeatable quality control data. An intuitive, touchscreen interface handles setup, operation, analysis and report generation. The 4D InSpec can also be mounted on a robotic manipulator for fully automated measurements of complex components.

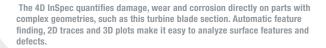
The included software automatically locates defects and calculates their height, volume, area, slopes and location. The operator can choose from 2D traces or 3D plots to view defects in great detail. The system also supports easy data transfer to quality control systems for rapid pass-fail analysis.

A complete 4D InSpec system includes the instrument, computer with HD 1080p touch-screen interface, single Ethernet cable tether and software. A portable workstation and Li-ion rechargeable battery with up to 8 hours of operational time are also available.



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nSpec[®] Surface Gauge

Specifications

Description

4D InSpec Surface Gauge

4D InSpec control and analysis software

XYZ point cloud, CSV file, or 2D Trace

450 nm LED with 100,000 hour MTBF

< 2 lbs (0.8 kg) instrument only

50-86° F (10-30° C)

150G (1*10-8/kg/s2)

< 98% non-condensing

10 ft (3 m); longer length optional

Basic Specifications Acquisition Measurable Range Field of View (module) Lateral Sampling Vertical Resolution Mounting Standoff Distance

Instantaneous, non-contact 3D surface measurement Defects and features 0.0002-0.1 in (5 µm-2.5 mm) deep/tall 0.3 x 0.3 in (7.7 x 7.7 mm) Lateral Sampling 0.00016 in (4.0 µm) 0.00016 in (4.0 µm) Handheld, microscope stand, or robotic mounting possible 1.4 in (35 mm)

Single snapshot; enhanced resolution multi-snapshot mode

Identify features based on height, area, and width thresholds

Contour, 3D, XY slice with arbitrary cursors, radius of curvature

Tabular feature analysis statistics with 3D surface maps

11 x 2 x 2.8 inches (280 mm x 50 mm x 70 mm)

1900x1900 pixels, 12-bit scientific CMOS camera

Max height, volume, area, max slope, density, aspect ratio, XY location

Masking based on signal to noise ratio; rectangular ROI masks for analysis

< 10 W 4D InSpec unit; < 250 W with computer system @ 120 VAC

Software

Analysis Measurement Modes Defect Detection **Defect Calculations** Data Displays Data Output Data Masking Export Computer

Electrical/Mechanical

Dimensions Light Source Sensor Power Consumption Weight Cable Length **Operating Temperature** Operating Humidity Shock resistance

Performance

Noise Floor Vertical Repeatability Step Height Accuracy Depth of Focus Minimum Part Roughness

< 0.00016 inches (4.0 µm) 1 < 0.00001 inches (0.15 $\mu m)$ $^{\rm 2}$ < 1% 3 > 0.10 inches (2.5 mm) 2.5 µin (60 nm) Ra

Warranty

One Year, limited

1 Average Ra of difference between two measurements on 4D calibration sample.

2 1 Ra for 30 measurements on 4D calibration sample.

3 Difference vs. PTB-certified values sample for features from 0.00039-0.035 in (100-900 μm) tall.

4 1 standard deviation on 30 measurements of 50 µm tall feature.

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All specifications subject to change without notice.

4D Technology Corp is a Nanometrics business unit



